The T2000 IPS (Integrated Power Device Test Solution) provides high-performance, high-throughput testing of devices for automotive and power management applications.

The T2000 offers a comprehensive set of feature-rich capabilities for testing devices used in automotive and power management applications. It also contributes to significantly reducing test costs by delivering increased throughput while maintaining high quality testing.

**Solutions for Testing Integrated Power Devices**

- High density instrument set for lowest cost-of-test
- Parallel test methods enabled by multifunctional modules
- Simplified load board design reduces need for external circuit
- Reliable glitch-free operation protects DUT and ATE
- Various function sets for best-in-class test time

**T2000 LSMF Addresses Automotive Applications & Power Management ICs:**

- Standardized configurations cover a wide device portfolio
- Flexible system architecture enables high multi-site implementation
- Configurable to add high speed digital and others
- Meets high pin count device and massive parallel requirements

**T2000 GSMF Addresses Low Pin-Count Power Management ICs:**

- Slim configurations optimized for small pin count devices
- Low infrastructure cost reduces initial investment

Conventional Modules

- PMU
- HV-Digital
- AWG/DGT

Cost of-Test savings

- >30%

Multi-function Module

- MMXH

Cost reduction benefit by adopting a multi-function module
- T2000 IPS module

**MMXH (Multi-function MiXed High voltage Module)**
- 32ch High Voltage DCL (24V/40Mbps)
- 32ch High Voltage PMU (-30V… +85V, 240mA)
- AWG, DGT per pin
- TMU per pin
- 2 differential voltmeters
- 8 IDDQ measurement units

**MFHP (Multi-function Floating High Power Module)**
- 6ch Floating High Power PMU (Max. 12A)
- ±80V output voltage, ±160V stackable
- 1:2 output multiplexer
- AWG, DGT per pin
- TMU per pin

**GPWGD (General Purpose Waveform Generator Digitizer)**
- 8ch arbitrary waveform generator
- 8ch digitizer
- 16ch PMU
- 8ch voltage reference

**250MDMA (250Mbps Digital Module)**
- 128ch I/O
- Per Pin PMU

**250MDMA (250Mbps Digital Module)**
- 128ch I/O
- Per Pin PMU

**1GDM (1.1Gbps Digital Module)**
- 256ch I/O
- Per Pin PMU

**MPCM (Multi-function Power Cross Point Matrix Module)**
- 72 power nodes
- 24ch PMU
- Overvoltage protection
- Full solid state design

<table>
<thead>
<tr>
<th>T2000 IPS mainframe (MF)</th>
<th>LSMF</th>
<th>LSMF</th>
<th>GSMF</th>
</tr>
</thead>
<tbody>
<tr>
<td>Number of test head (TH) slots</td>
<td>52</td>
<td>26</td>
<td>13</td>
</tr>
<tr>
<td>MF size (W x D x H) mm</td>
<td>800 x 1050 x 1600</td>
<td>800 x 1050 x 1600</td>
<td>450 x 1000 x 960</td>
</tr>
<tr>
<td>TH size (W x D x H) mm</td>
<td>790 x 1120 x 797</td>
<td>790 x 800 x 780</td>
<td>480 x 800 x 780</td>
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<tr>
<td>Cooling</td>
<td>Liquid</td>
<td>Air/Liquid</td>
<td>Air</td>
</tr>
</tbody>
</table>

- Please refer to the product manual for complete system specifications.
- Specifications may change without notification.

http://www.advantest.co.jp

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